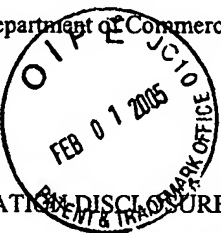



U.S. Department of Commerce, Patent and Trademark Office  INFORMATION & DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Application No.:	10/748,827
	Filing Date:	December 29, 2003
	First Named Inventor:	Joonhyung Kwon
	Group Art Unit:	2856
	Examiner Name:	Larkin, Daniel Sean
	Confirmation No.:	7166
	Attorney Docket No.:	PSI004-1C US

U.S. Patent Documents								
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
		US 5,672,816	09/1997	Park et al.	73	105		
<i>DM</i>		US 3,600,811	08/1971	Weyrauch, Adolf	33	707		
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)								
<i>DM</i>	AQ	Binnig G., et al, "Atomic Force Microscope", Physical Review Letters, vol 56, No. 9, Mar. 3, 1986 pp. 930-933.						
	AR	Hansma, P.K., et al, "A new optical-lever based atomic force microscope", J. Appl. Phys., 76(2) Jul. 15, 1994, American Institute of Physics, pp. 796-799.						
	AS	Meyer, Gerhard et al, "Erratum: Novel optical approach to atomic force microscopy", Appl. Phys. Lett. 53(24), Dec. 12, 1988, American Institute of Physics, pp. 2400-2402.						
	AT	"Dimensions 3100 Scanning Probe Microscope The Most Versatile SPM Ever Manufactured", www.di.com/Products/Dim/3100/D3100Main.html, Digital Instruments, Veeco Metrology Group © 1998-2001, print date Dec. 17, 2001, 4 pages.						
	AY	"Dimension 3100 Scan Techniques Unparalleled Power and Versatility", www.di.com/Products/Dim/3000/D31.scantechniques.html, Digital Instruments Veeco Metrology Group, ©1998-2001, print date Dec. 17, 2001, 2 pages.						
	AZ	AutoProbe M5™ Scanning Probe Microscope, Microscopes Veeco Metrology Group, 2001© TM Microscopes, Veeco, 4 pages.						
	BA	"TappingMode Imaging: Application and Technology", www.di.com/AppNotes/TapMode/TapModeMain.html, Digital Instruments, Veeco Metrology Group, ©1995-2001, Digital Instruments, print date Dec. 17, 2001, 5 pages.						
<i>DM</i>	BB	"NanoScope Vertical Engage Scanner", www.di.com/Products/Mult/JVScanner.html, Digital Instruments Veeco Metrology Group, ©1996-2001, Digital Instruments, print date Dec. 17, 2001, 1 page.						

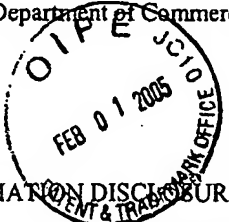
Examiner: <i>[Signature]</i>	Date Considered: <i>25 April 2005</i>
* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.	

* The Park et al. reference was previously considered in the IDS filed 29 December 2003.


U.S. Department of Commerce, Patent and Trademark Office  INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Application No.:	10/748,827
	Filing Date:	December 29, 2003
	First Named Inventor:	Joonhyung Kwon
	Group Art Unit:	2856
	Examiner Name:	Larkin, Daniel Sean
	Confirmation No.:	7166
	Attorney Docket No.:	PSI004-1C US

U.S. Patent Documents								
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
<i>Dr</i>		US 5,666,051	09/1997	Junker et al.	324	209		
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)								
<i>Dr</i>	BC	"NanoScope MultiMode Scanning Probe Microscope", www.di.com/products/Multi/MMAIone.html, Digital Instruments Veeco Metrology Group, © 1996-2001, Digital Instruments, 8 page.						
	BD	"NanoScope ® MultiMode™ SPM The World's Highest Resolution SPM", www.di.com/Products/Multi/MMMain.html, Digital Instruments Veeco Metrology Group, ©1995-2001, Digital Instruments, print date Dec. 17, 2001 7 pages.						
	BE	"Products", Digital Instruments, Veeco Metrology Group Products, www.di.com/products2/products_all.html, print date Dec. 17, 2001, 5 pages.						
	BF	"AutoProbe CP Research The Most Flexible Research SPM", www.theermomicro.com/products/cp.htm, Microscopes Veeco Metrology Group, ©2001, print date Dec, 17, 2001, 2 pages.						
	BG	Manalis, S. R., et al, "High-speed atomic force microscopy using an integrated actuator and optical lever detection", Rev. Sci. Instrum. 67(9), Sep. 1996, pp. 3294-3297.						
	BH	"Microlevers™ General Purpose Cantilevers", Park Scientific Instruments © 1998, 1 page.						
	BI	Babcock, K.L. et al. "Phase Imaging: Beyond Topography", Digital Instruments, 3 pages, published prior to Feb. 15, 2002						
	BJ	"AutoProbe CP Research AP 2001", ThermoMicroscopes, 5 pages, published prior to Feb. 15, 2002						
<i>Dr</i>	BK	"AutoProbe CP Research Scanning Probe Microscope", ThermoMicroscopes, 4 pages, published prior to Feb. 15, 2002						

Examiner: <i>Dr. L. Z.</i>	Date Considered: <i>25 April 2005</i>
* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.	

U.S. Department of Commerce, Patent and Trademark Office  INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Application No.:	10/748,827
	Filing Date:	December 29, 2003
	First Named Inventor:	Joonhyung Kwon
	Group Art Unit:	2856
	Examiner Name:	Larkin, Daniel Sean
	Confirmation No.:	7166
	Attorney Docket No.:	PSI004-1C US

U.S. Patent Documents								
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
DZ		US 2001/0029674	10/2001	Cutler, Donald R.	33	1.00M		
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)								
DZ	BL	"AutoProbe MSE AP-5001", ThermoMicroscopes, 4 pages, published prior to Feb. 15, 2002						
	BM	"The Dimension TM 5000 Scanning Probe Microscope", Digital Instruments, 8 pages, published prior to Feb. 15, 2002						
	BN	"The Dimension TM 3000 Scanning Probe Microscope", Digital Instruments, 6 pages, published prior to Feb. 15, 2002						
	BO	"The Dimension TM 3100 Scanning Probe Microscope", Digital Instruments, 1 page, published prior to Feb. 15, 2002						

Examiner: 	Date Considered: 25 April 2005
* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.	